Sear	ch No	tes	

Application No.

10/033,979

Examiner

Fritz Alphonse

Applicant(s)

HAN SU PAE ET AL.

Art Unit

2133

SEARCHED						
CI	ass	Subclass	Da	ate	Exam	iner
3	45	76	2/18/2005		FA	
		77				
		78				
		79				
		80				
		82				
		204		,		
		55				
3	15	169.3				
		,				
				_		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
345	76; 78	2/18/2005	FA		
	204				

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
345/\$.ccls. (active near4 matrix or TFT) and deviation near4 compensat\$4 and converter same current same display same volt\$4	2/18/2005	FA
and comparator same converter same reference near4 voltage and (sample and hold or s and H) near4 circuit		